

<b>Notice of References Cited</b>	Application/Control No. 10/055,088	Applicant(s)/Patent Under Reexamination SAGATELIAN ET AL.	
	Examiner Cynthia Britt	Art Unit 2133	Page 1 of 1

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	U	"Early Error Detection in Systems-on-Chip for Fault-Tolerance and At-Speed Debugging" by Sogomonyan et al. 19th IEEE Proceedings on VLSI Test Symposium Publication Date: 29 April-3 May 2001 pages184 - 189 Inspec Accession Number: 7023720
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.